## Search Notes Application/Control No. Applicant(s)/Patent Under Reexamination BLASI ET AL. Examiner Jacob, Mary C Art Unit 2123

SEARCHED							
Class		Subclass	Date	Examiner			
703	15		2/21/08	MCJ			

SEARCH NOTES					
Search Notes	Date	Examiner			
Updated Inventor Name Search: EAST	2/21/08	MCJ			
Updated Assignee Name Search: EAST	2/21/08	MCJ			
Updated East Search: See search History	2/21/08	MCJ			
Google Scholar: catalog, memory model, test bench generator; "memory model", test bench generator, ports, synchronous, asynchronous, catalog or database or repository	2/21/08	MCJ			
IEEE: test bench generator, memory models, catalog or repository or database; catalog or repository or database near4 memory models; test bench generation and memory models	2/21/08	MCJ			

INTERFERENCE SEARCH							
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	PG Pub Text Search: see search history printout	2/21/08	MCJ				

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